

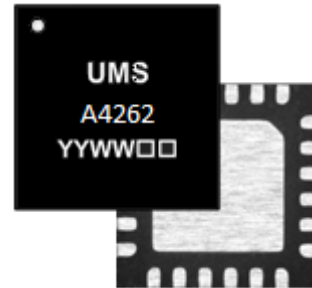
## 17 - 22 GHz Medium Power Amplifier GaAs Monolithic Microwave IC

### Description

The CHA4262-QDG is a three-stage GaAs Medium Power Amplifier operating between 17GHz and 22GHz. This amplifier provides 23dBm saturated output power with 37% Power Added Efficiency and 20dBm Output Power at 1dB gain compression. The circuit exhibits a typical small signal gain of 26dB and 30dBm Output Third-Order Intercept Point.

This Medium Power Amplifier is dedicated to Space applications and it is also ideal for a wide range of microwave systems.

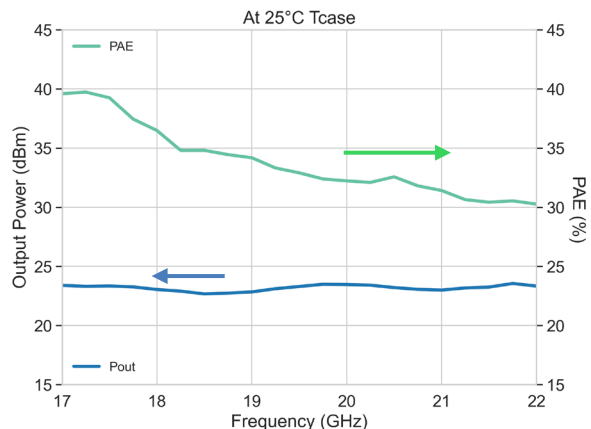
This new product is matched to 50Ω and supplied on RoHS 4 mm x 4 mm QFN plastic package.



### Main Features

- Frequency band: 17-22GHz
- 23dBm P<sub>OUT</sub> at 37% PAE
- 26dB small signal gain
- NPR = 12dBc at 22dBm Average Pout<sup>(1)</sup>
- Typical DC bias: V<sub>D</sub> = 2.5V@I<sub>DQ</sub> = 130mA
- 24L-QFN 4x4mm<sup>2</sup>
- MSL3

<sup>(1)</sup> Bandwidth = 1GHz, Notch = 10%



### Main Electrical Characteristics

T<sub>case</sub> = +25°C, V<sub>d</sub> = +2.5V (T<sub>case</sub> : QFN backside temperature)

Symbol	Parameter	Min	Typ	Max	Unit
Frequency	Frequency range	17		22	GHz
Gain	Small signal Gain		26		dB
P <sub>SAT</sub>	Saturated Output power (Pin = 5dBm)		23		dBm
PAE	Power Added Efficiency (Pin = 5dBm)		37		%
NPR	Noise power ratio (Pin = 5dBm)		12		dBc
I <sub>DQ</sub>	Quiescent Drain Current		130		mA

## Electrical Characteristics

$T_{case} = +25^{\circ}\text{C}$ ,  $V_d = +2.5\text{V}$  ( $T_{case}$  : QFN backside temperature)

Symbol	Parameter	Min	Typ	Max	Unit
Freq	Frequency range	17		22	GHz
Gain	Small Signal Gain		26		dB
IRL	Input return loss		-13		dB
ORL	Output return loss		-13		dB
Psat	Saturated Output power ( $P_{in} = 5\text{dBm}$ )		23		dBm
P1dB	Output Power @1dB Gain compression		20		dBm
OIP3	Output Third-Order Intercept Point		30		dBm
NPR	Noise power ratio ( $P_{in} = 5\text{dBm}$ )		12		dB
PAE	Power Added Efficiency ( $P_{in} = 5\text{dBm}$ )		37		%
NF	Noise Figure		3.5		dB
$I_{DQ}$	Quiescent Drain Current		130		mA

These values are representative of on-board measurements as defined on the drawing in paragraph "Evaluation board".

## Absolute Maximum Ratings <sup>(1)</sup>

$T_{case} = +25^{\circ}\text{C}$

Symbol	Parameter	Values	Unit
$V_d$	Drain bias voltage	3.5V	V
$I_d$	Drain bias current	200	mA
$V_g$	Gate bias voltage	-2 to +0.4	V
$P_{in}$	Maximum peak input power overdrive	+7	dBm

<sup>(1)</sup> Operation of this device above anyone of these parameters may cause permanent damage.

## Recommended Operating Range <sup>(2), (3)</sup>

Symbol	Parameter	Values	Unit
$V_d$	Drain bias voltage	2 to 3	V
$I_{DQ}$	Quiescent Drain Current	90 to 150	mA
$V_g$	Gate voltage (typical)	-0.45	V
$P_{in}$	Maximum peak input power overdrive <sup>(2)</sup>	+5	dBm
$T_j$	Junction temperature	175	$^{\circ}\text{C}$
$T_{case}$	QFN backside temperature range	-30 to +95	$^{\circ}\text{C}$
$T_{stg}$	Storage temperature range	-55 to +150	$^{\circ}\text{C}$

<sup>(2)</sup> Electrical performances are defined for specified test conditions

<sup>(3)</sup> Electrical performances are not guaranteed over all recommended operating conditions

**Typical Bias Conditions** $T_{\text{case}} = +25^{\circ}\text{C}$ 

Symbol	Parameter	Value	Unit
VG1, VG2, VG3	Typical gate bias voltage tuned for $I_{DQ} = 130\text{mA}$	-0.45	V
VD1, VD2, VD3	Drain bias voltage	2.5	V

**“Power ON” sequence**

1. Ground the device
2. Set the gate voltage to -1.5V
3. Apply the drain voltage  $V_d$  (typically +2.5V)
4. Increase  $V_g$  up to quiescent bias drain current  $I_{DQ}$
5. Apply RF signal

**“Power OFF” sequence**

1. Turn off RF signal
2. Decrease the gate voltage to -1.5V
3. Decrease the drain voltage to 0V
4. Turn off  $V_d$  supply
5. Turn off  $V_g$  supply

**Device thermal performances**

All the figures given in this section are obtained assuming that the QFN device is only cooled down by conduction through the package thermal pad (no convection mode considered).

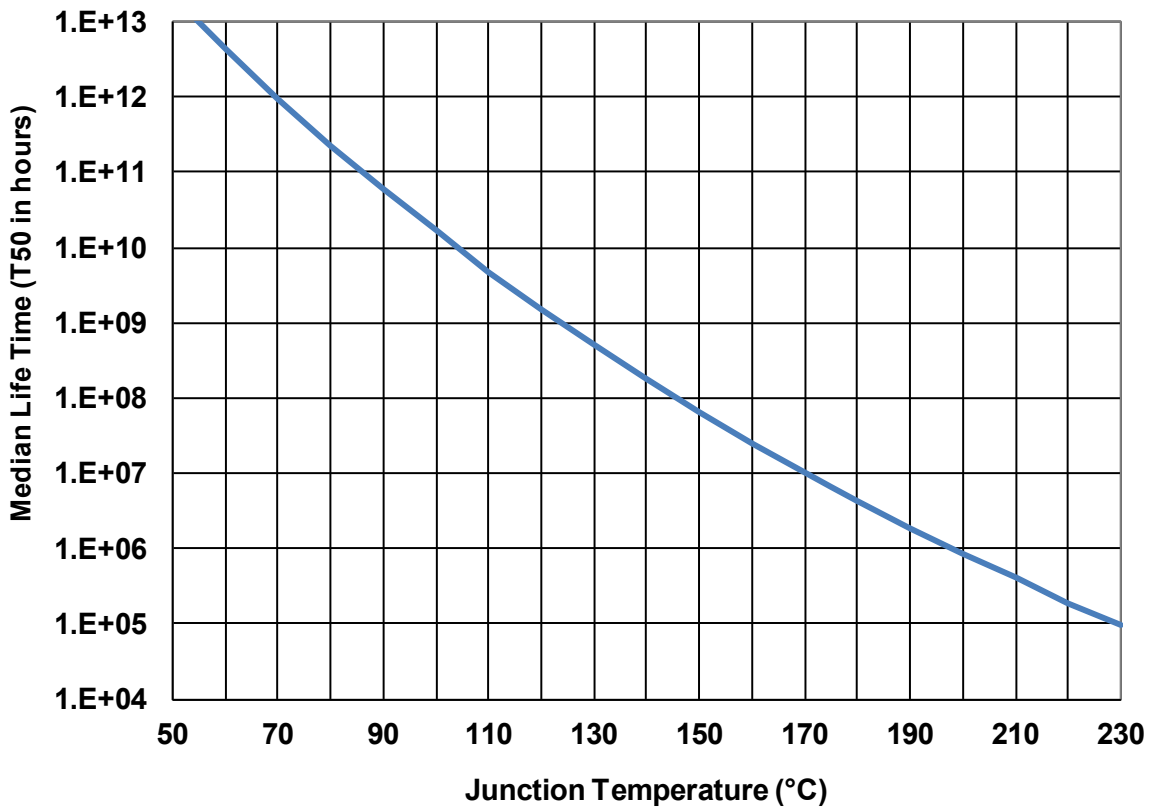
The temperature is monitored at the package backside interface ( $T_{case}$ ).

For nominal operating conditions, the system maximum temperature must be adjusted in order to guarantee that  $T_j$  remains below the maximum value specified in the Recommended Operating Ratings table. The system PCB must be designed to comply with this requirement.

Parameter	Biasing conditions	$T_j$ (°C)	$R_{TH}$ (°C/W)	T50 (hours)
$R_{TH}^{(1)}$ Thermal Resistance (Junction to QFN Backside)	Vd=2.5V Pout=23dBm Pdis=0.45W	102	37.2	1.27E+10
	Vd=2.5V Small Signal Pdis=0.3W	98	40.7	2.09E+10

(1) Assuming 85°C  $T_{case}$

**Median Life Time versus Junction Temperature**

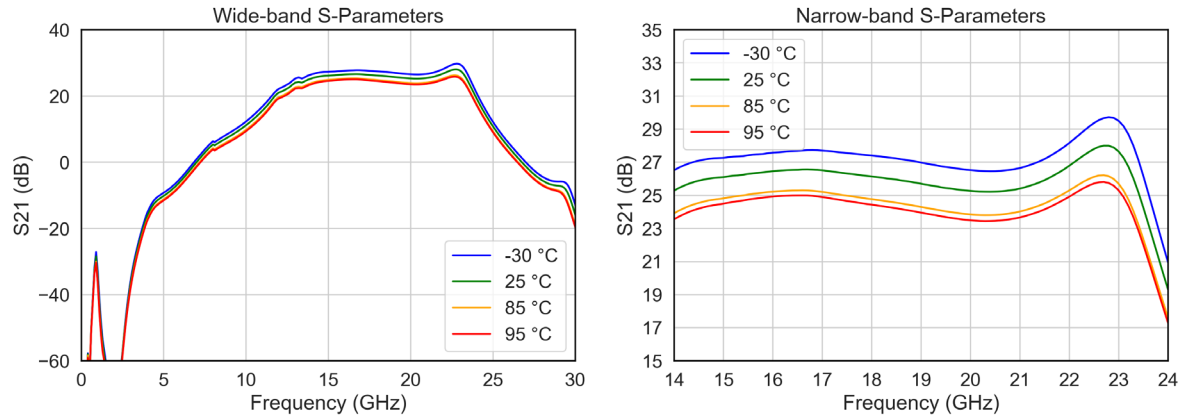


## Typical on Board Measurements

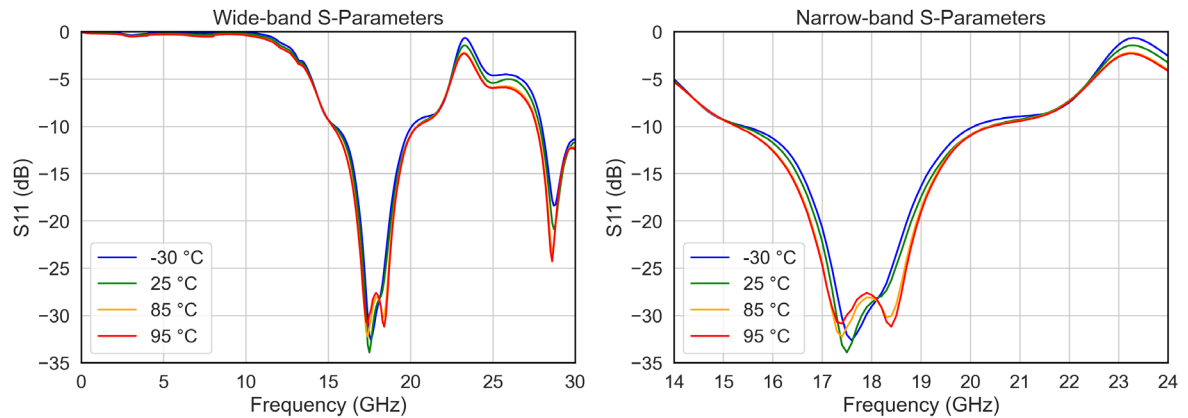
**Test conditions :**  $T_{case} = -30^{\circ}C/+25^{\circ}C/85^{\circ}C/95^{\circ}C$ ,  $V_d = 2.5V$ ,  $I_{dq} = 130mA$

Board losses are de-embedded. Measurements are given in the package access plans.

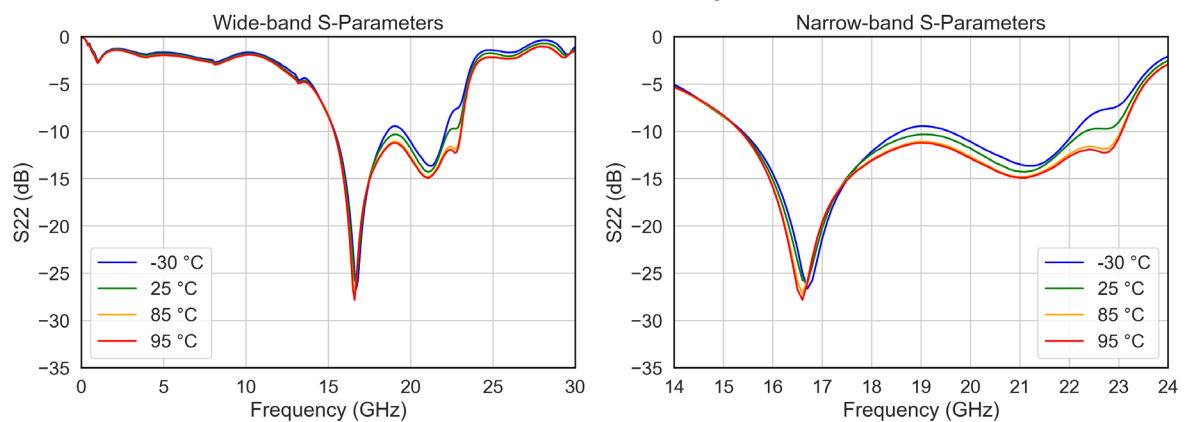
### Linear Gain vs. Frequency & Temperature



### Input Return Loss vs. Frequency & Temperature



### Output Return Loss vs. Frequency & Temperature

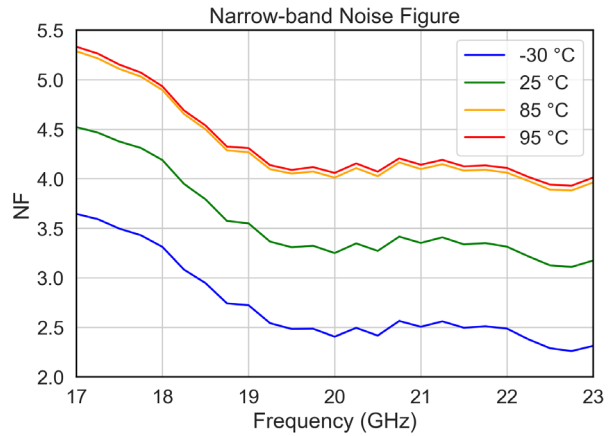
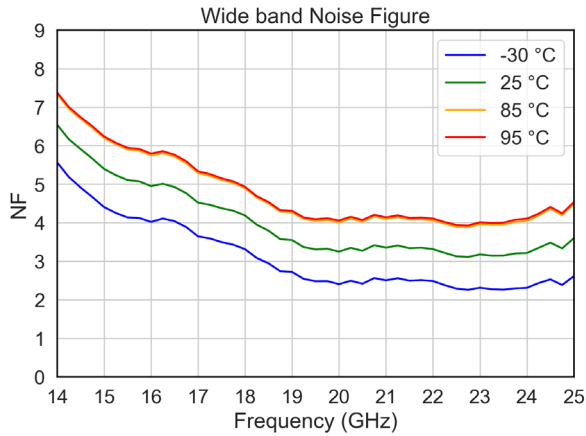


## Typical Board Measurements

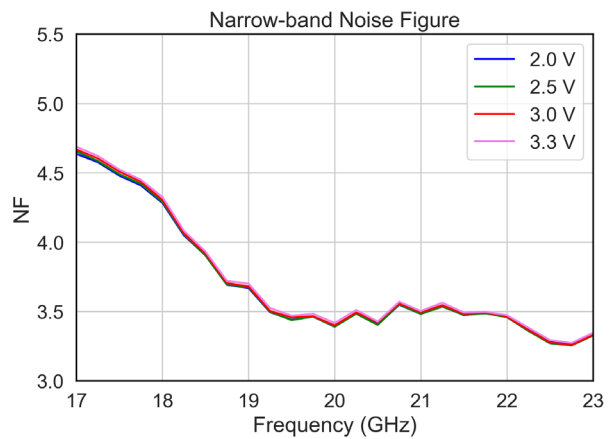
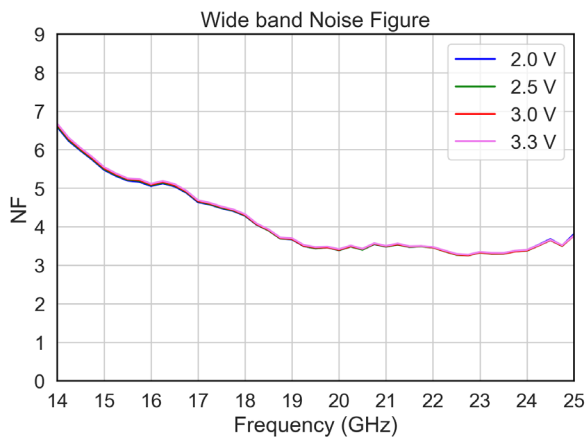
**Test conditions :**  $T_{case} = -30^{\circ}\text{C}/+25^{\circ}\text{C}/85^{\circ}\text{C}/95^{\circ}\text{C}$ ,  $V_d = 2\text{V}/2.5\text{V}/3\text{V}/3.3\text{V}$ ,  
 $I_{dq} = 90\text{mA}/130\text{mA}/150\text{mA}$

Board losses are de-embedded. Measurements are given in the package access plans.

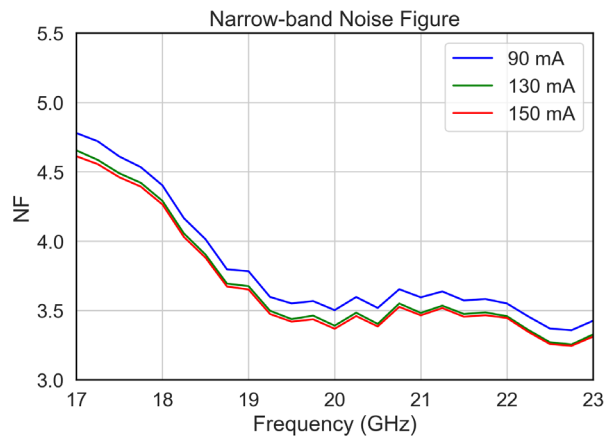
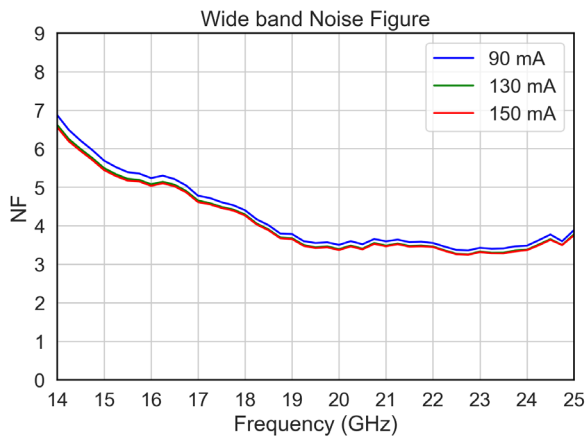
### Noise Figure vs. Frequency & Temperature at $V_d = 2.5\text{V}$ & $I_{dq} = 130\text{mA}$



### Noise Figure vs. Frequency & Drain voltage at $I_{dq} = 130\text{mA}$ & Temp = $25^{\circ}\text{C}$



### Noise Figure vs. Frequency & Current at $V_d = 2.5\text{V}$ & Temp = $25^{\circ}\text{C}$

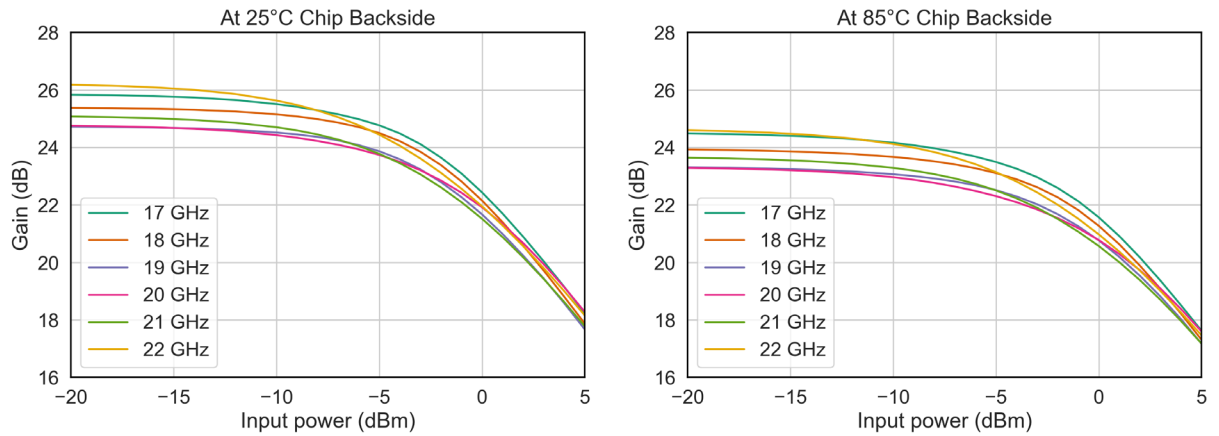


## Typical Board Measurements

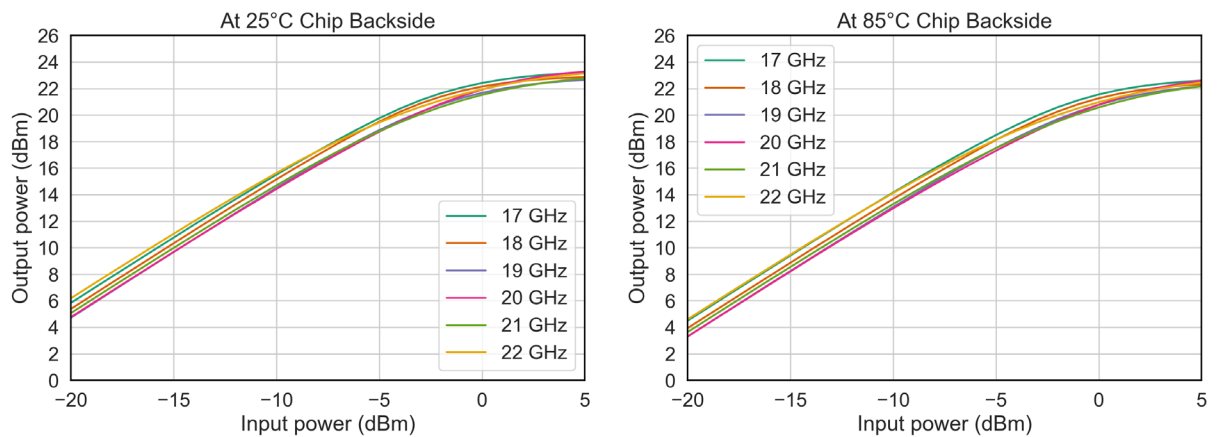
**Test conditions :**  $T_{case} = +25^{\circ}\text{C}/85^{\circ}\text{C}$ ,  $V_d = 2.5\text{V}$ ,  $I_{dq} = 130\text{mA}$

Board losses are de-embedded. Measurements are given in the package access plans.

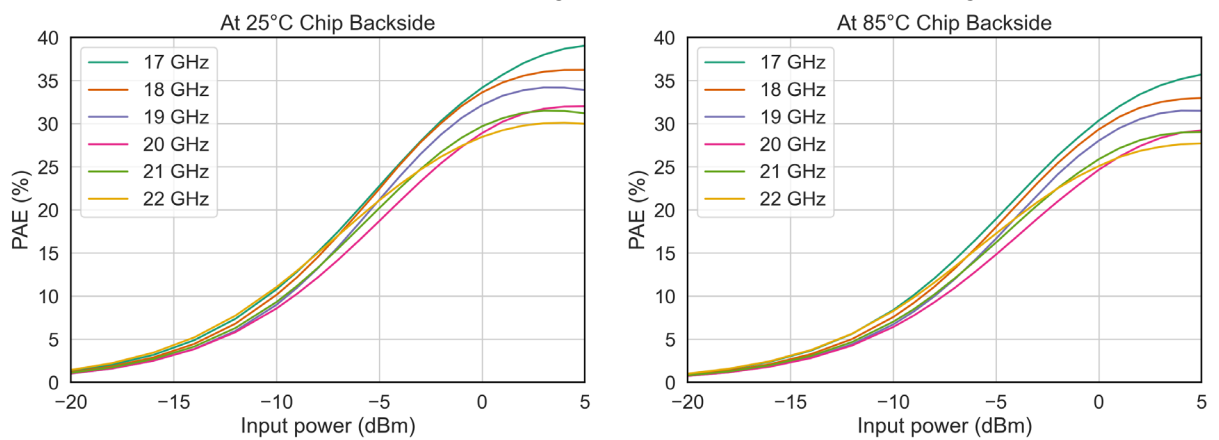
### Gain vs. Input Power & Frequency



### Output Power vs. Input Power & Frequency



### Power Added Efficiency vs. Input Power & Frequency

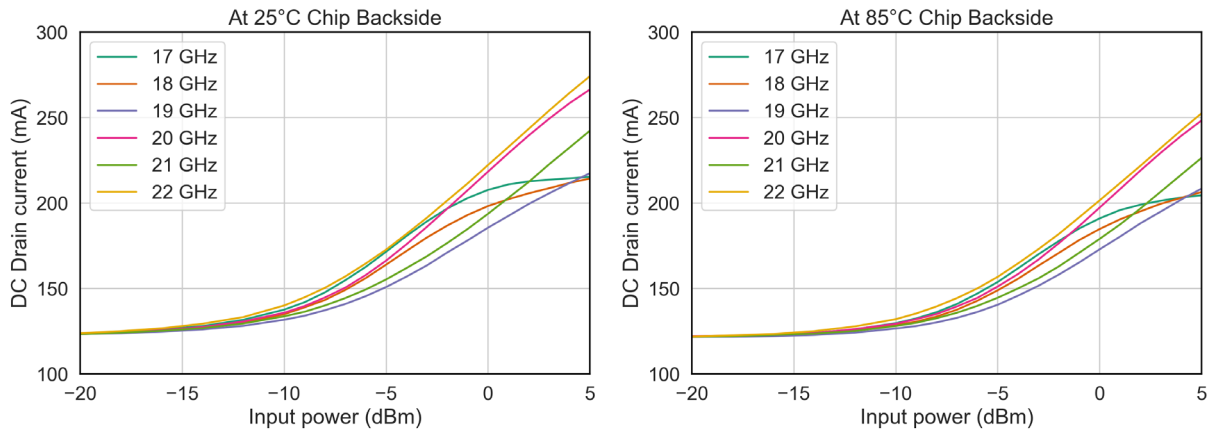


## Typical Board Measurements

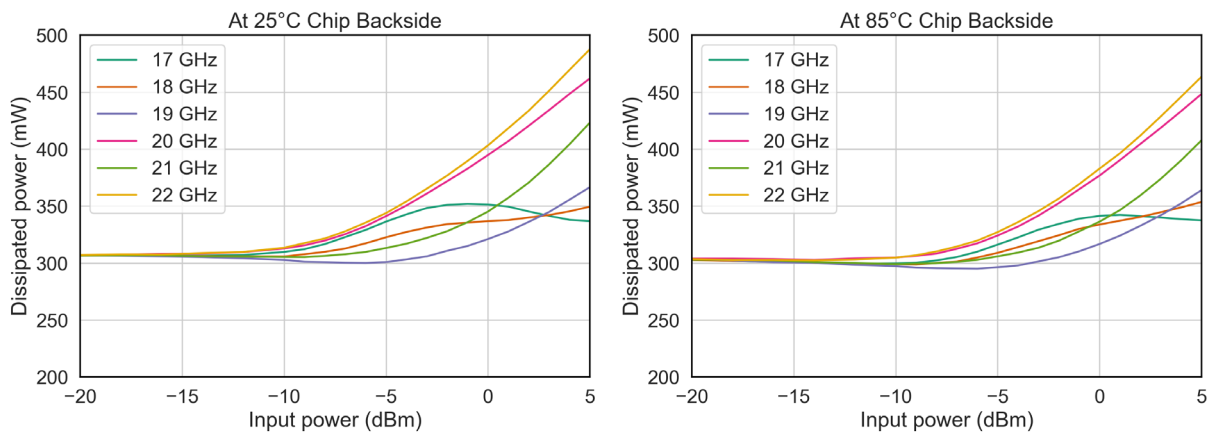
**Test conditions :**  $T_{case} = +25^{\circ}C/85^{\circ}C$ ,  $V_d = 2.5V$ ,  $I_{dq} = 130mA$

Board losses are de-embedded. Measurements are given in the package access plans.

### Drain Current vs. Input Power & Frequency



### Dissipated Power vs. Input Power & Frequency

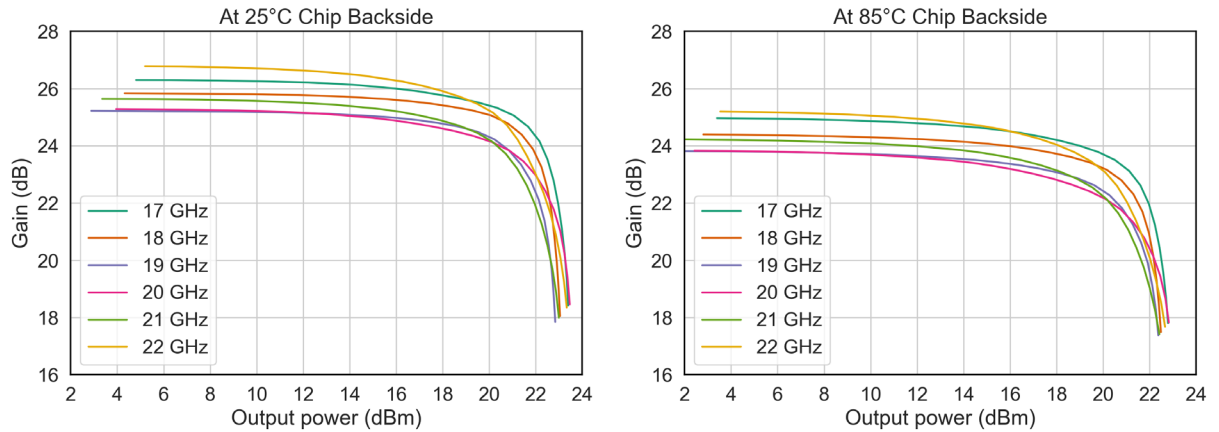


## Typical Board Measurements

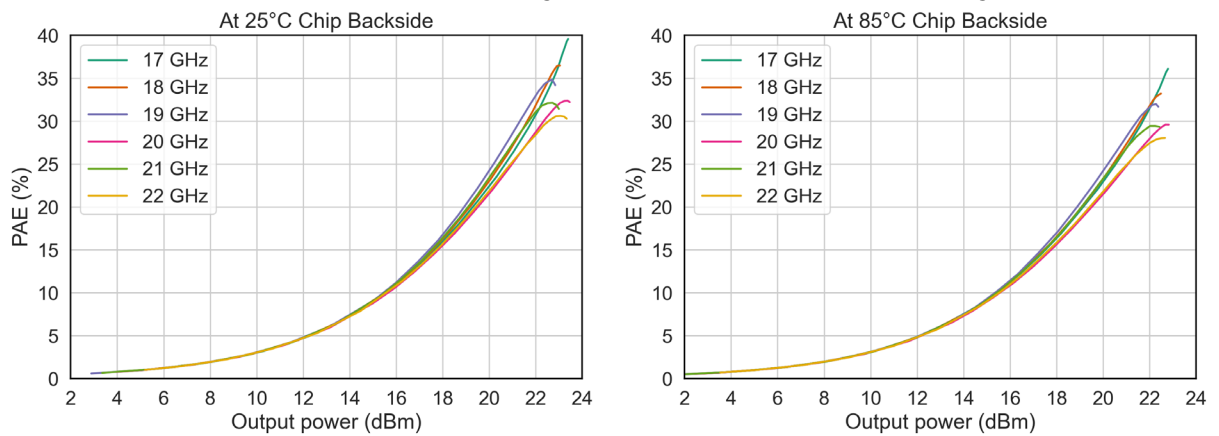
**Test conditions :**  $T_{case} = +25^{\circ}C/85^{\circ}C$ ,  $V_d = 2.5V$ ,  $I_{dq} = 130mA$

Board losses are de-embedded. Measurements are given in the package access plans.

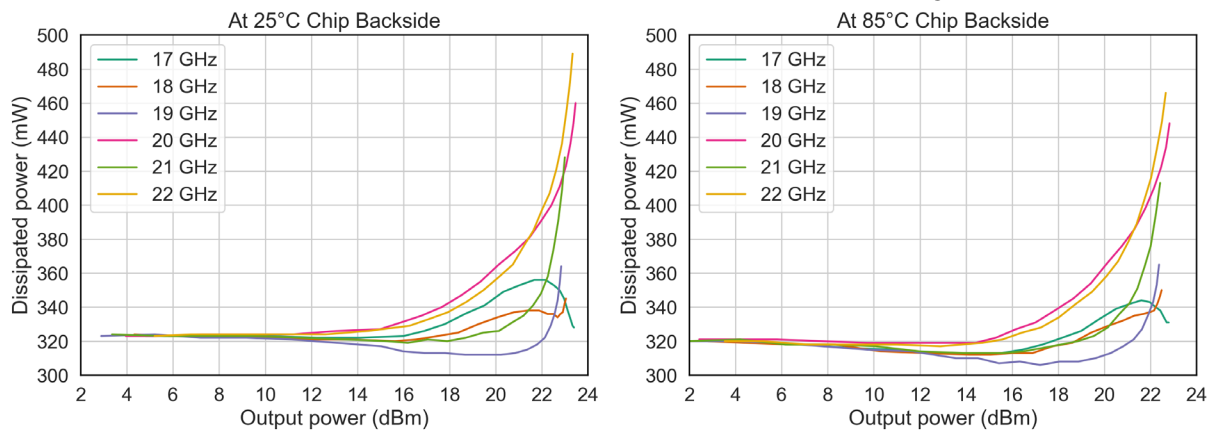
### Gain vs. Output Power & Frequency



### Power Added Efficiency vs. Output Power & Frequency



### Dissipated Power vs. Output Power & Frequency

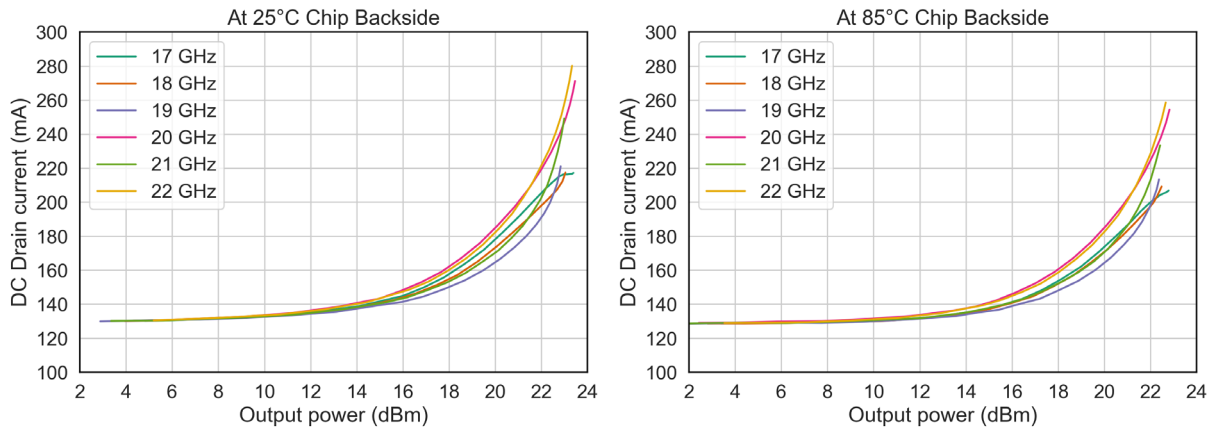


## Typical Board Measurements

**Test conditions :**  $T_{case} = +25^{\circ}C/85^{\circ}C$ ,  $V_d = 2.5V$ ,  $I_{dq} = 130mA$

Board losses are de-embedded. Measurements are given in the package access plans.

### Drain Current vs. Output Power & Frequency

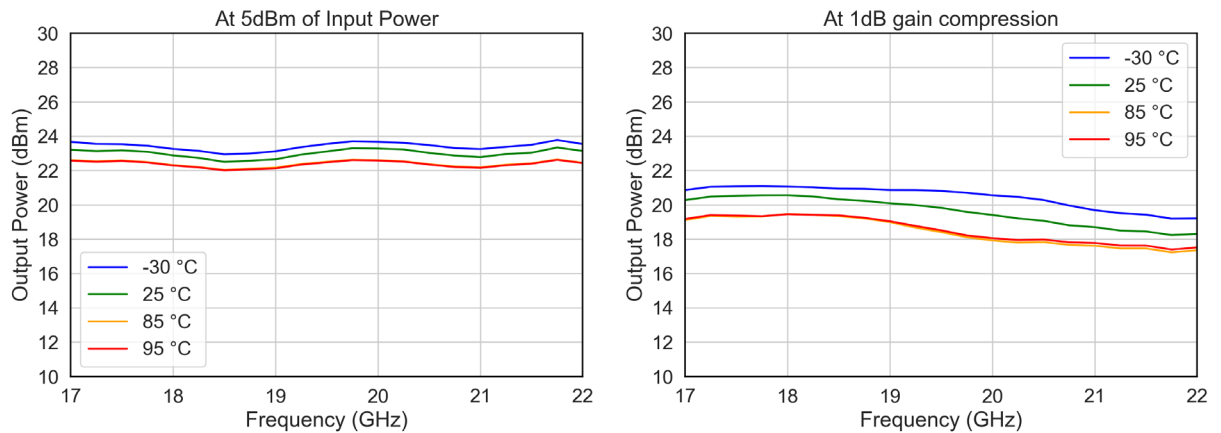


## Typical Board Measurements

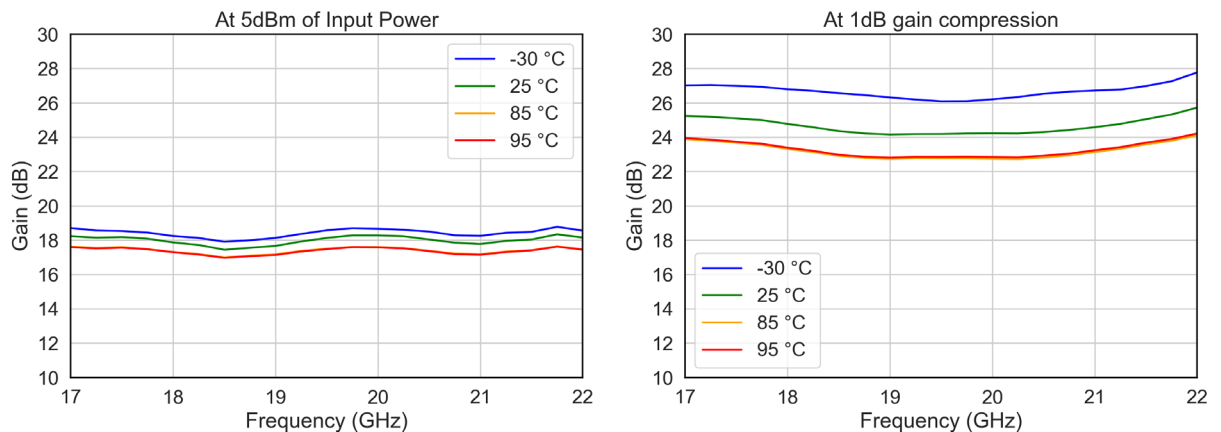
**Test conditions :**  $T_{case} = -30^{\circ}C/+25^{\circ}C/85^{\circ}C/95^{\circ}C$ ,  $V_d = 2.5V$ ,  $I_{dq} = 130mA$

Board losses are de-embedded. Measurements are given in the package access plans.

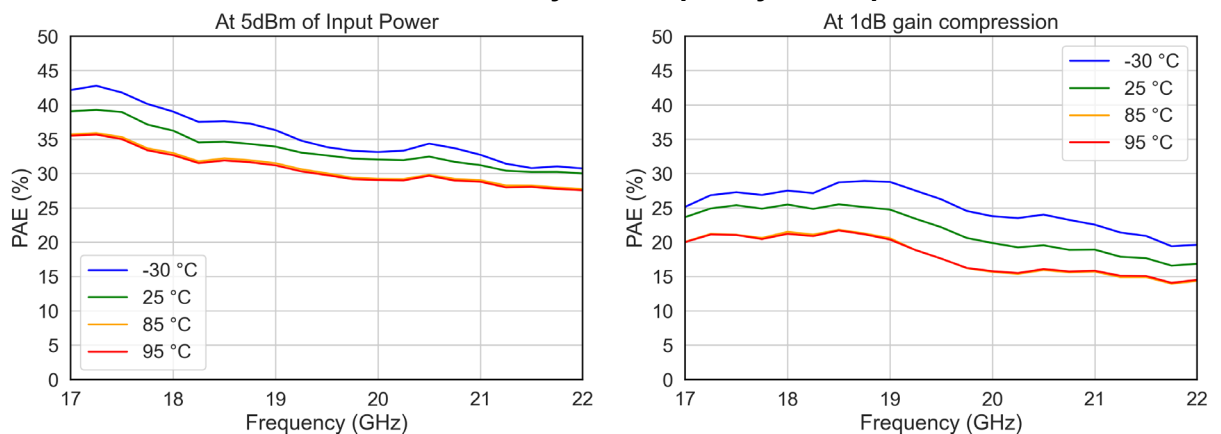
### Output Power vs. Frequency & Temperature



### Gain vs. Frequency & Temperature



### Power Added Efficiency vs. Frequency & Temperature

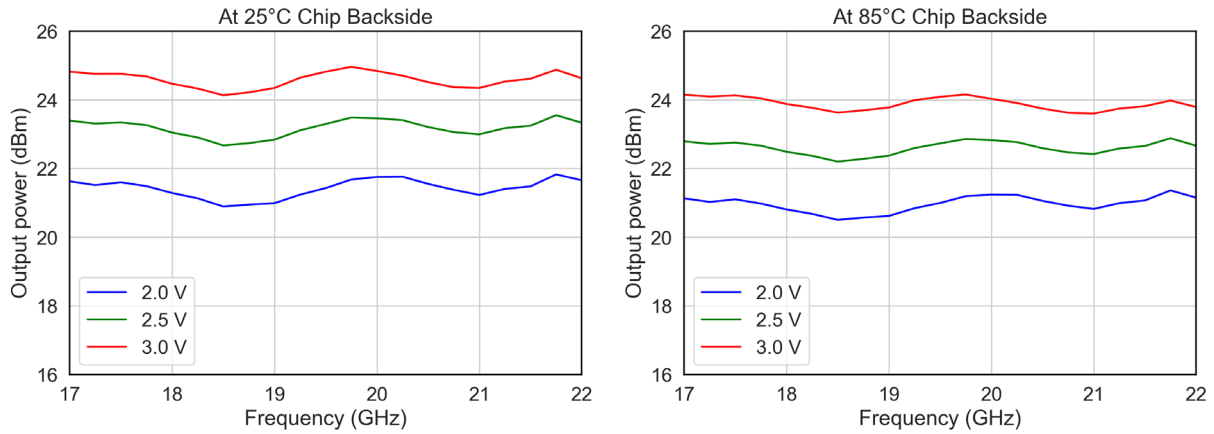


## Typical Board Measurements

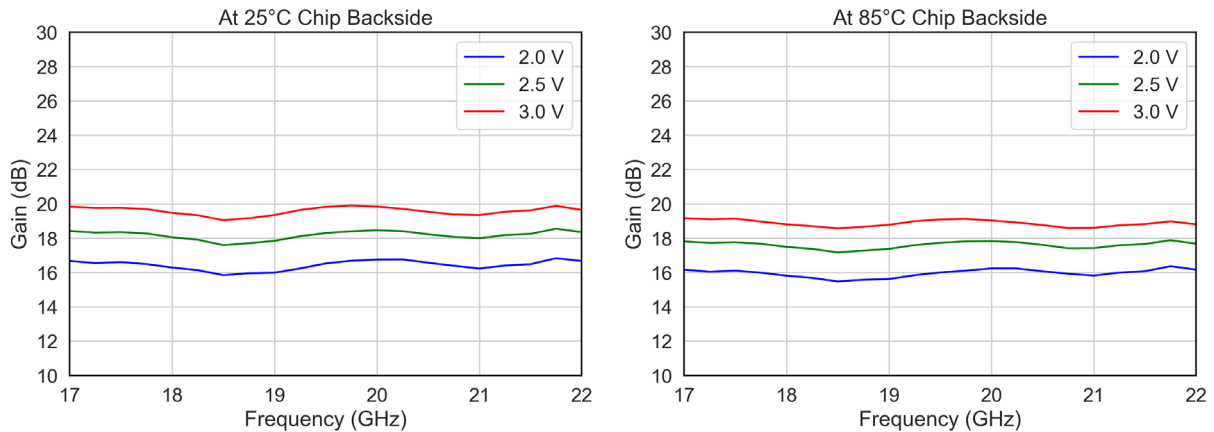
**Test conditions :**  $T_{case} = 25^{\circ}C$ ,  $V_d = 2V/2.5V/3V$ ,  $I_{dq} = 130mA$ ,  $P_{in}=5dBm$

Board losses are de-embedded. Measurements are given in the package access plans.

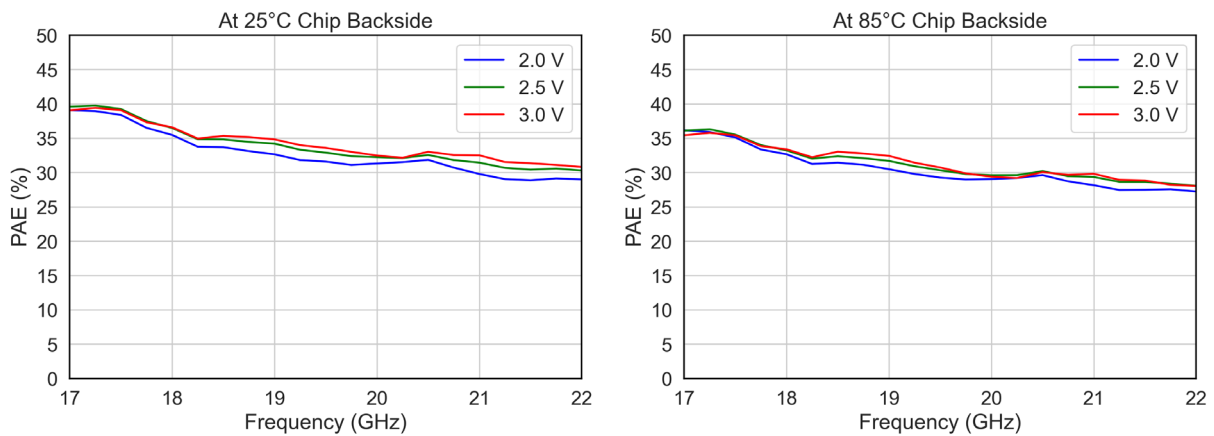
### Output Power vs. Frequency & Vd



### Gain vs. Frequency & Vd



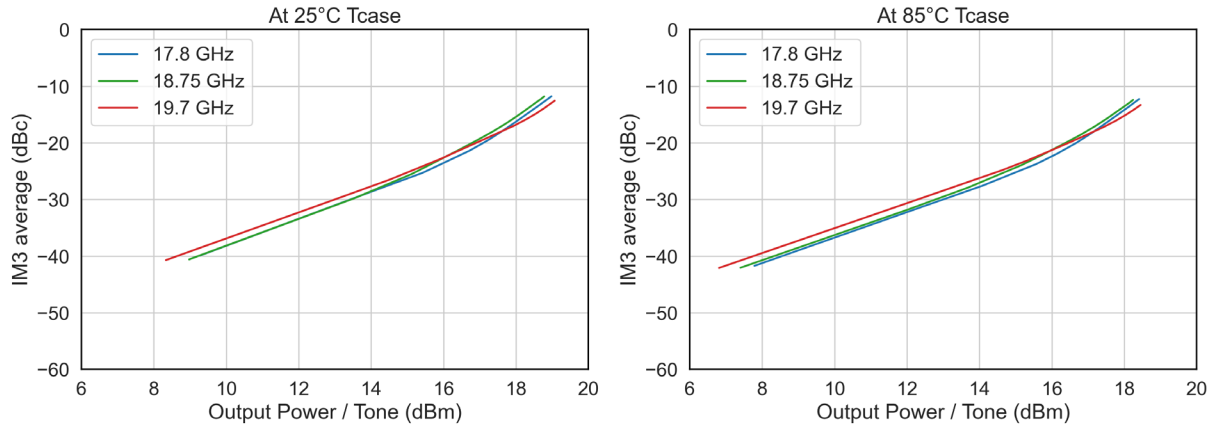
### Power Added Efficiency vs. Frequency & Vd



**Typical Board Measurements**

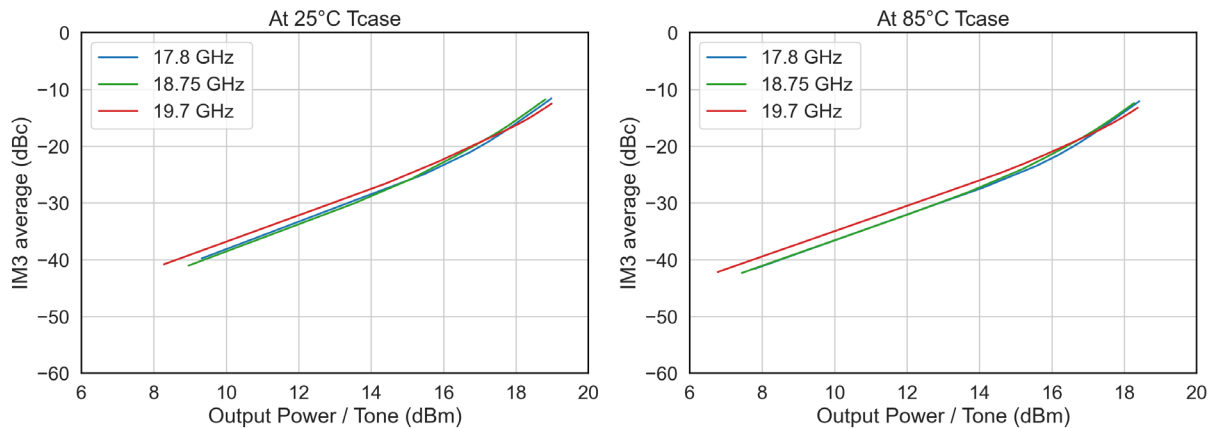
**Test conditions :** CW dual tones,  $V_d = +2.5V$ ,  $I_{dq} = 130mA$ ,  $\Delta f = 10MHz$ ,  $T_{case} = +25^\circ C/85^\circ C$

**IMD3 vs. Output Power per Tone & Frequency**



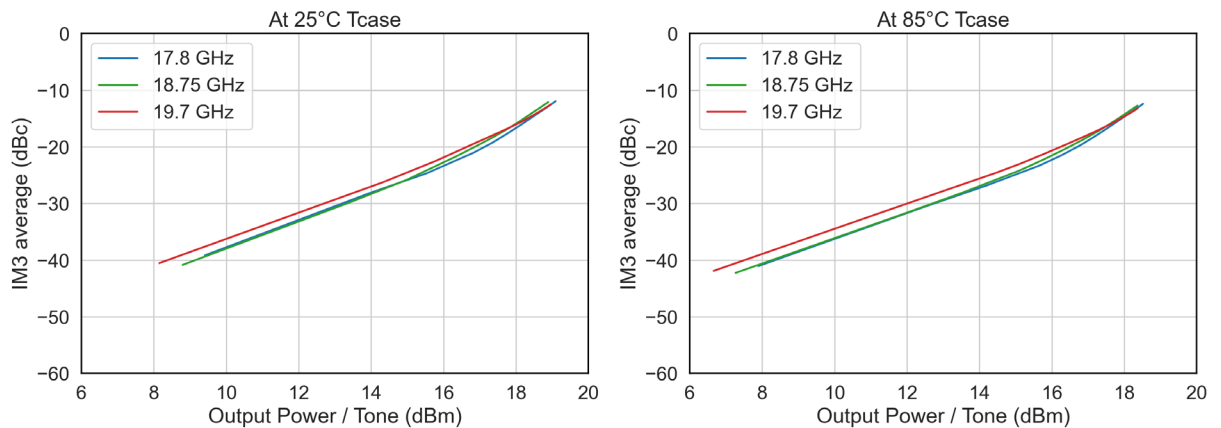
**Test conditions :** CW dual tones,  $V_d = +2.5V$ ,  $I_{dq} = 130mA$ ,  $\Delta f = 50MHz$ ,  $T_{case} = +25^\circ C/85^\circ C$

**IMD3 vs. Output Power per Tone & Frequency**



**Test conditions :** CW dual tones,  $V_d = +2.5V$ ,  $I_{dq} = 130mA$ ,  $\Delta f = 100MHz$ ,  $T_{case} = +25^\circ C/85^\circ C$

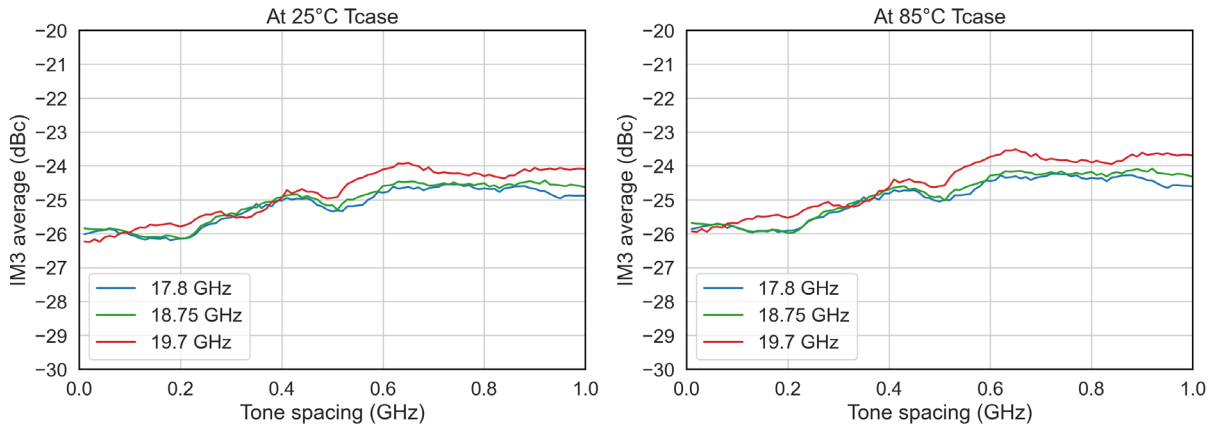
**IMD3 vs. Output Power per Tone & Frequency**



## Typical Board Measurements

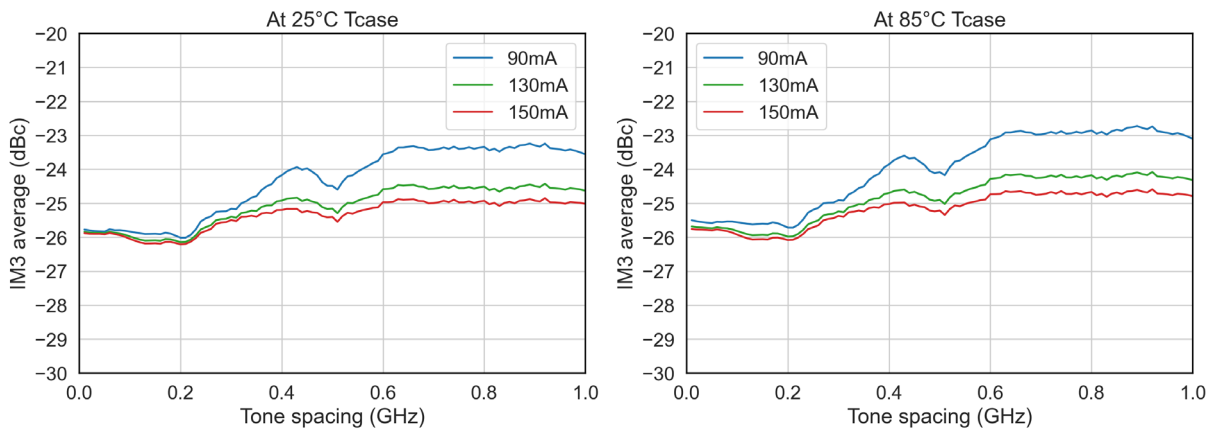
**Test conditions :** CW dual tones,  $V_d = +2.5V$ ,  $I_{dq} = 130mA$ ,  $P_{out}/tone = 14dBm$ ,  $T_{case} = +25^\circ C/85^\circ C$

### IMD3 vs. Tone Spacing & Frequency



**Test conditions :** CW dual tones,  $V_d = +2.5V$ ,  $F_c = 18.75GHz$ ,  $P_{out}/tone = 14dBm$ ,  $T_{case} = +25^\circ C/85^\circ C$

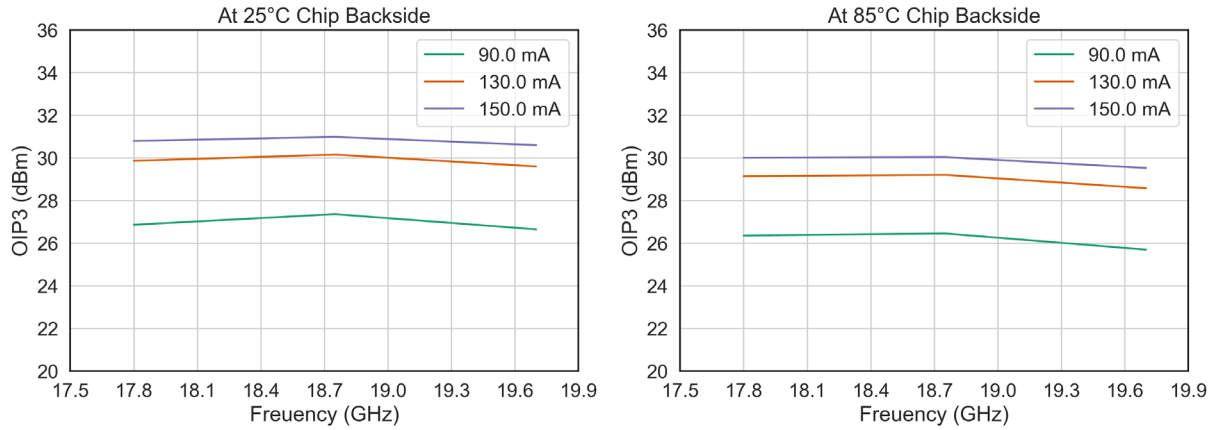
### IMD3 vs. Tone Spacing & Drain Current



**Typical Board Measurements**

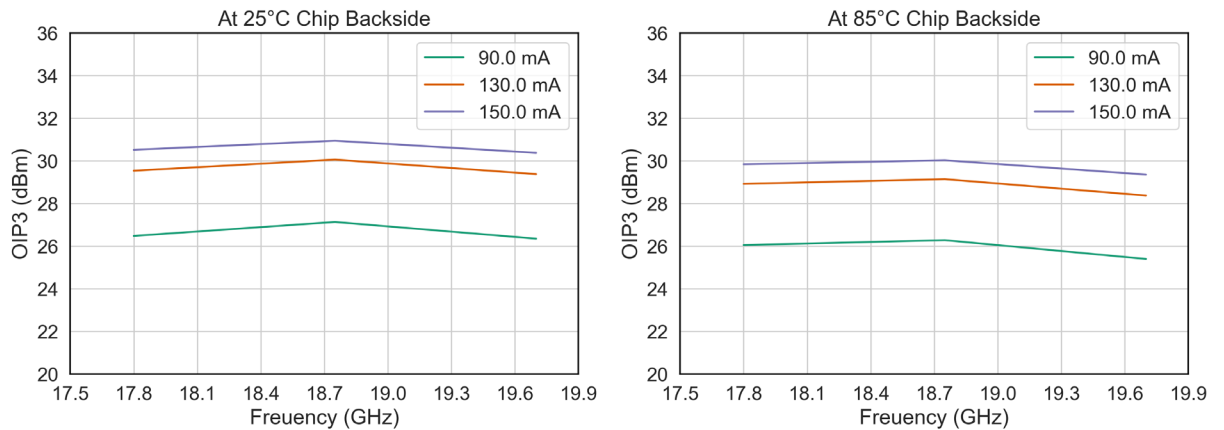
**Test conditions :** CW dual tones, Vd = +2.5V, Idq = 90,130,150mA, Δf = 10MHz, Pout/tone = -15dBm,

**OIP3 vs. Frequency & Quiescent Drain Current**



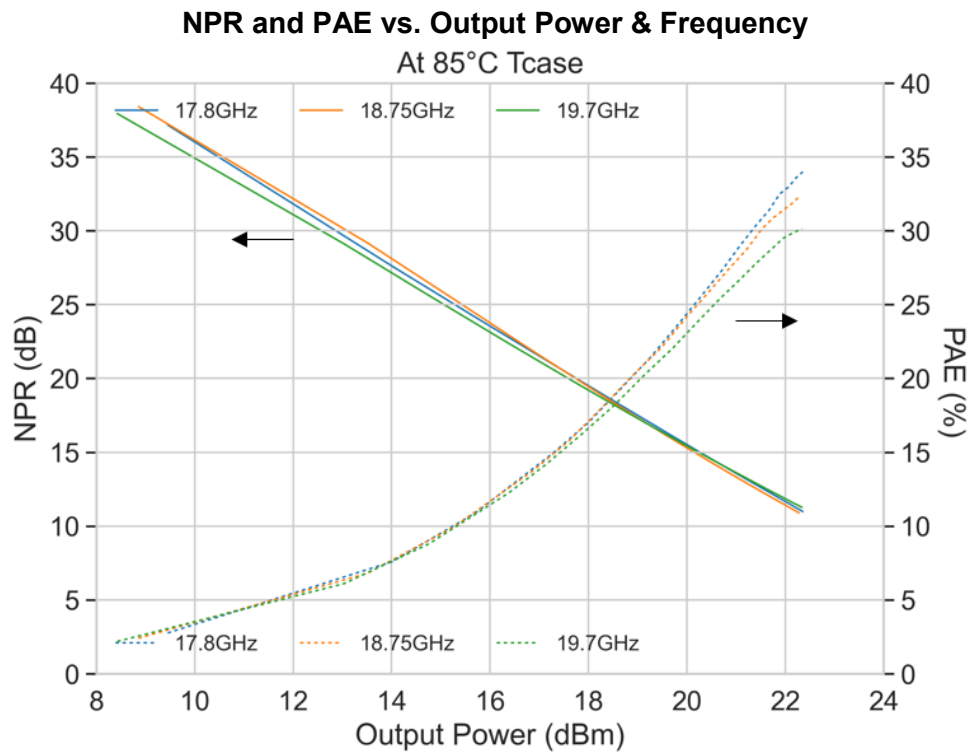
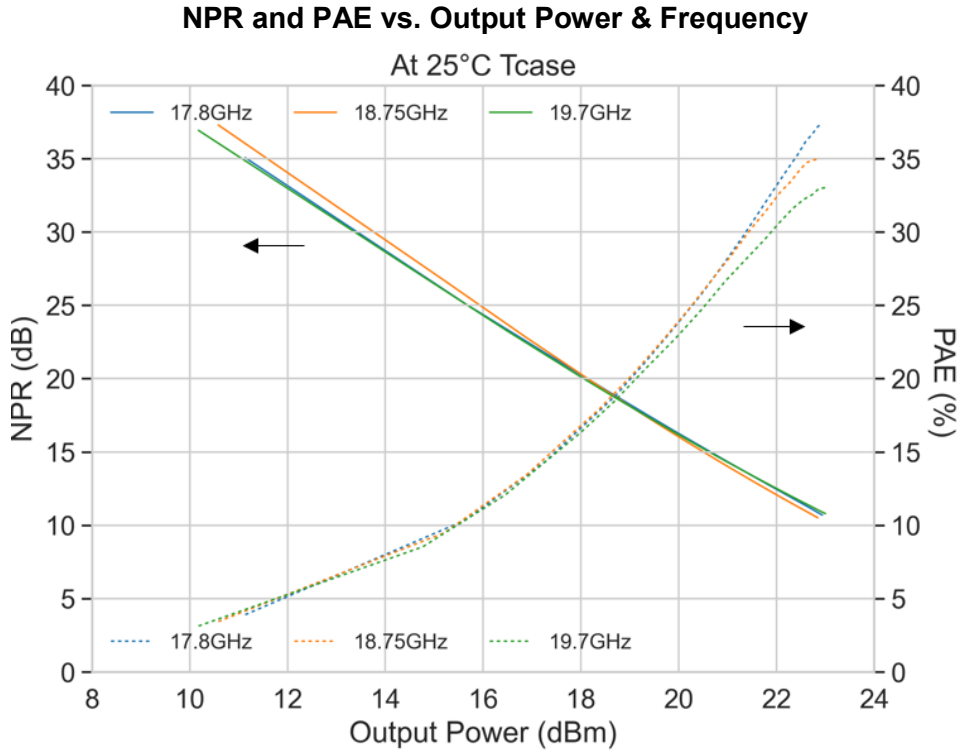
**Test conditions :** CW dual tones, Vd = +2.5V, Idq = 90,130,150mA, Δf = 100MHz, Pout/tone = -15dBm

**OIP3 vs. Frequency & Quiescent Drain Current**



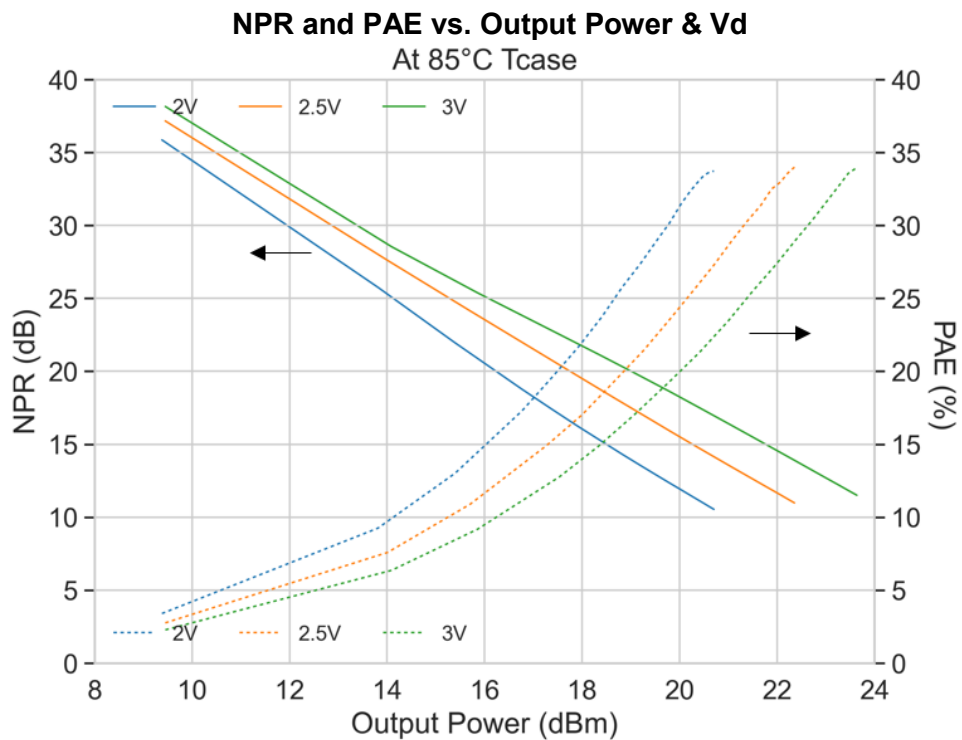
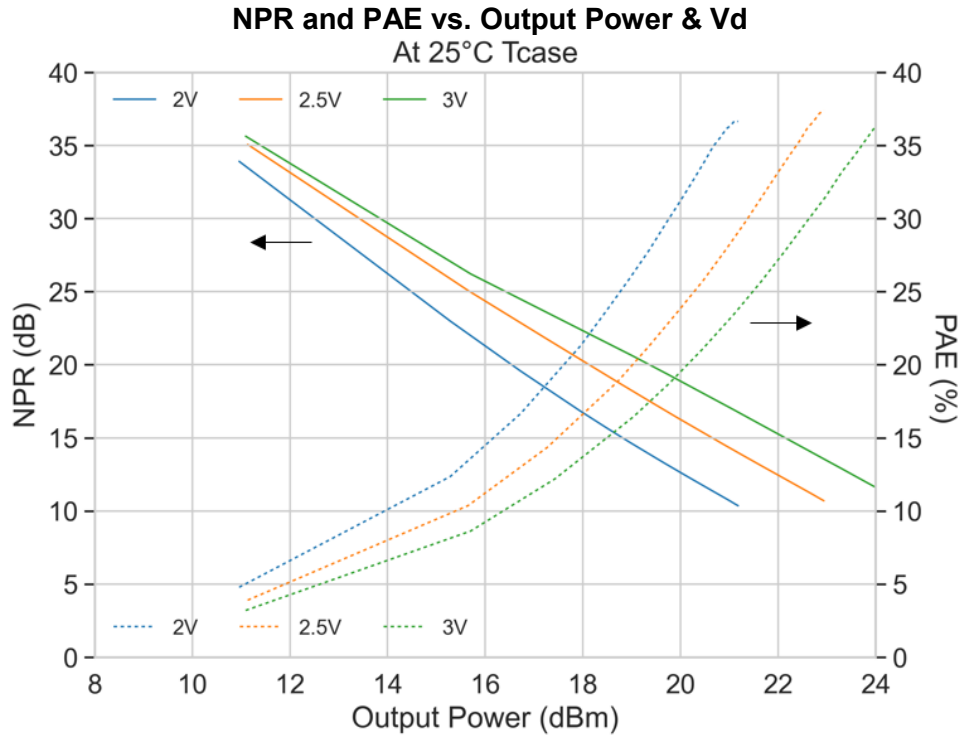
Typical Board Measurements

Test conditions :  $V_d = +2.5V$ ,  $I_{dq} = 130mA$ ,  $T_{case} = +25^\circ C/85^\circ C$ ,  
 Bandwidth = 1GHz, Notch = 10%

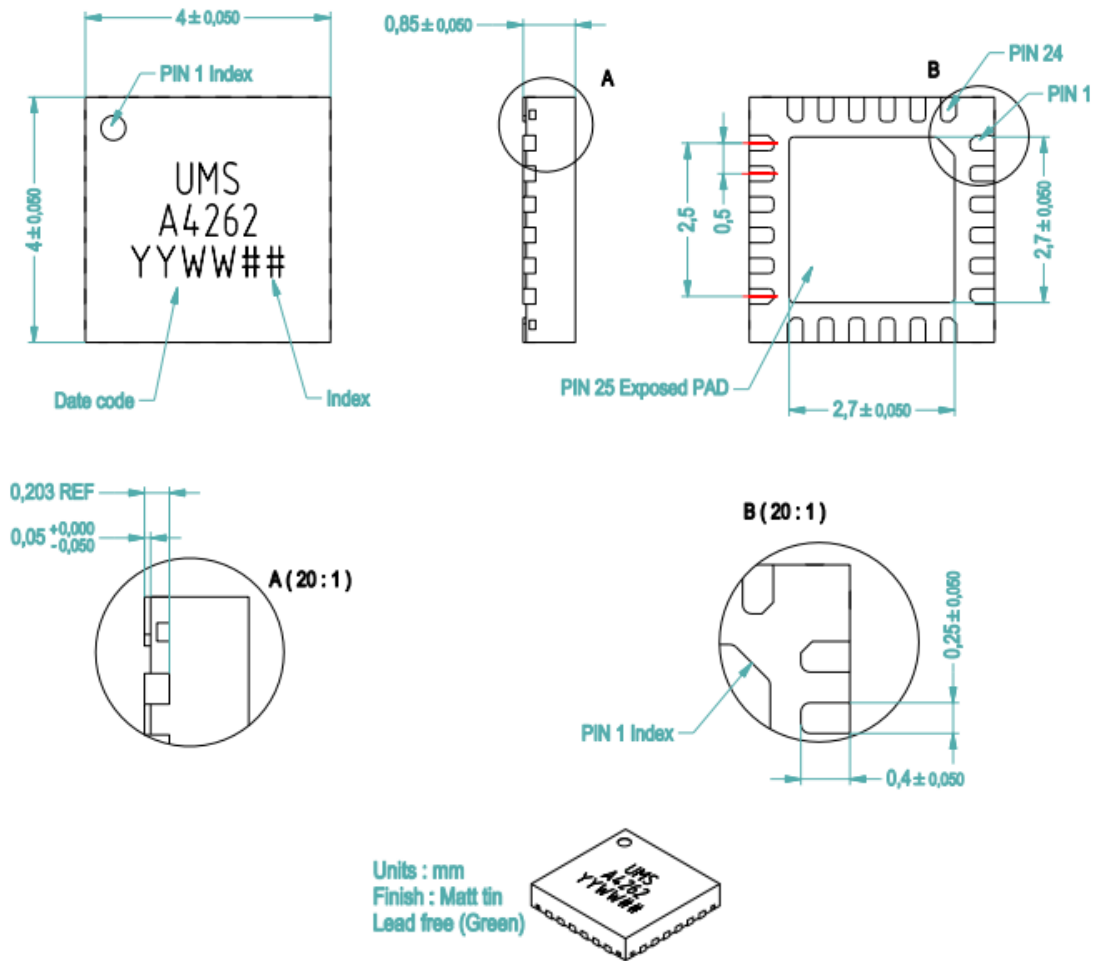


**Typical Board Measurements**

**Test conditions :**  $V_d = +2V/+2.5V/+3V$ ,  $I_{dq} = 130mA$ ,  $T_{case} = +25^{\circ}C/85^{\circ}C$ ,  
 Bandwidth = 1GHz, Notch = 10%, Freq = 17.8GHz



## Package outline (1)

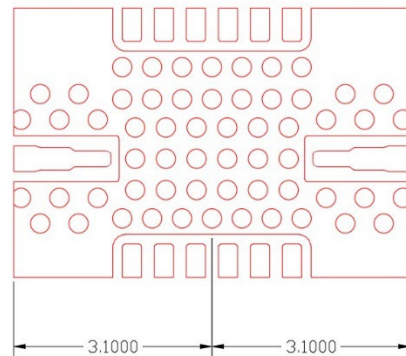


Finish:	Matt tin Lead Free (Green)	1- NC	10- VG3	19- NC
Units :	mm	2- GND <sup>(1)</sup>	11- GND <sup>(1)</sup>	20- GND <sup>(1)</sup>
From the standard :	JEDEC MO-220	3- GND <sup>(1)</sup>	12- NC	21- VD3
	(VGGD)	4- RF IN	13- GND <sup>(1)</sup>	22- VD2
NC :	Not Connected	5- GND <sup>(1)</sup>	14- GND <sup>(1)</sup>	23- VD1
		6- GND <sup>(1)</sup>	15- RF OUT	24- NC
		7- NC	16- GND <sup>(1)</sup>	25- GND <sup>(1)</sup>
		8- VG1	17- GND <sup>(1)</sup>	
		9- VG2	18- NC	

<sup>(1)</sup> It is strongly recommended to ground all pins marked "GND" through the PCB board. Ensure that the PCB board is designed to provide the best possible ground to the package.

## Definition of measurement reference planes

The reference planes used for measurements given above are symmetrical from the symmetrical axis of the package (see drawing beside). The input and output reference planes are located at 3.1mm offset (input wise and output wise respectively) from this axis.



## ESD sensitivity

Parameter	Classification	Standard
Human Body Model (HBM)	1A	ANSI/ESDA/JEDEC - JS-001

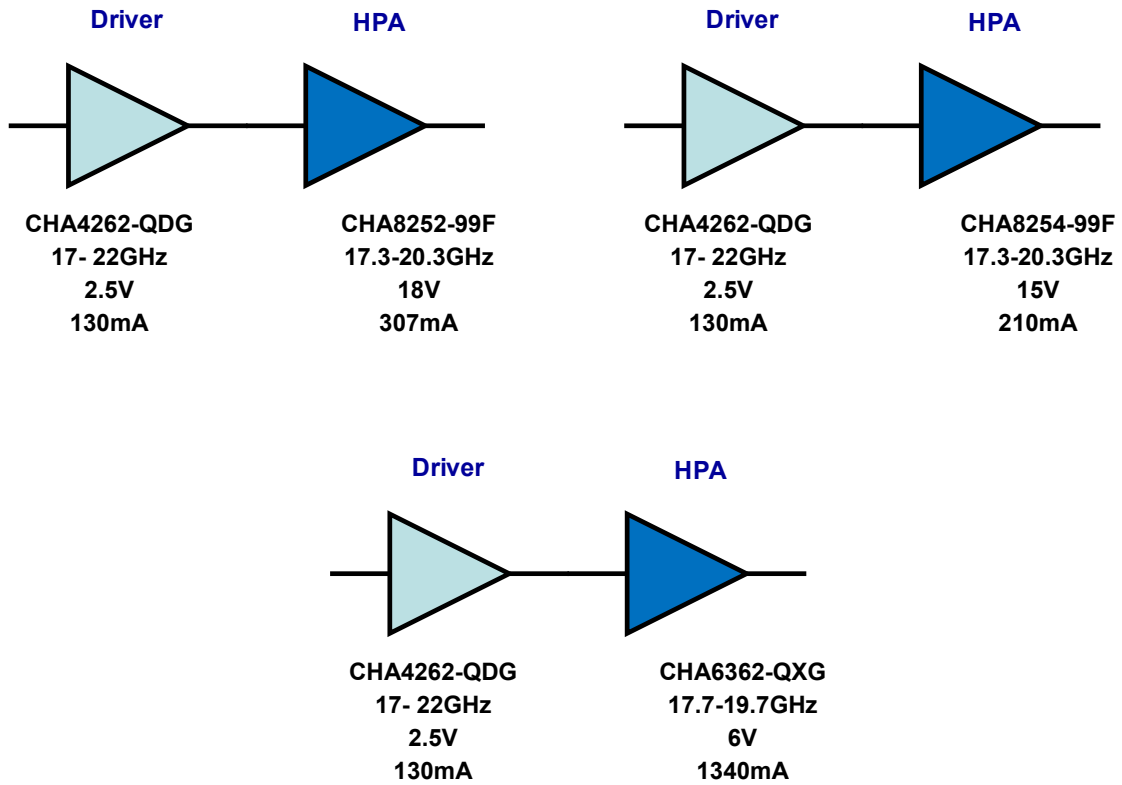
## Package Information

Parameter	Value
Package body material	RoHS-compliant
	Low stress Injection Molded Plastic
Lead finish	100% Matt Tin
Moisture Sensitivity Level	MSL3

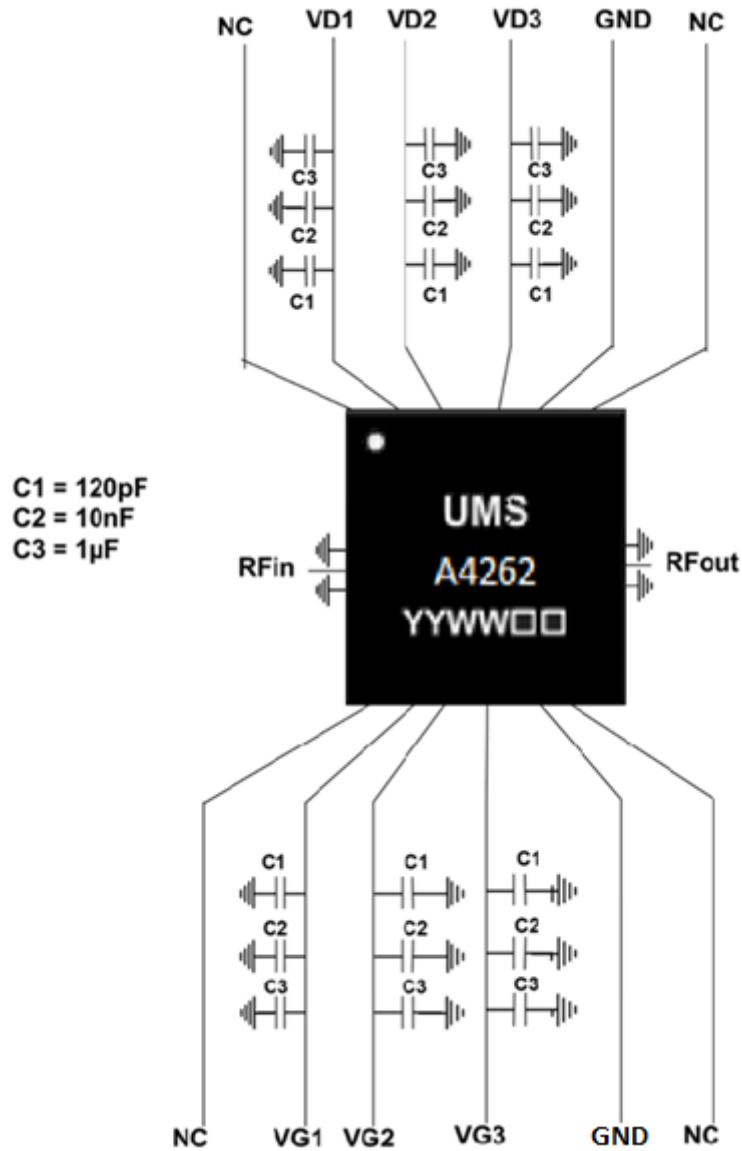
## Recommended UMS Power chain

The CHA4262-QDG is recommended with different HPA.

For more information about the CHA8252-99F, the CHA8254-99F and the CHA6362-QXG see our web site <https://www.ums-rf.com>



**Recommended assembly plan**



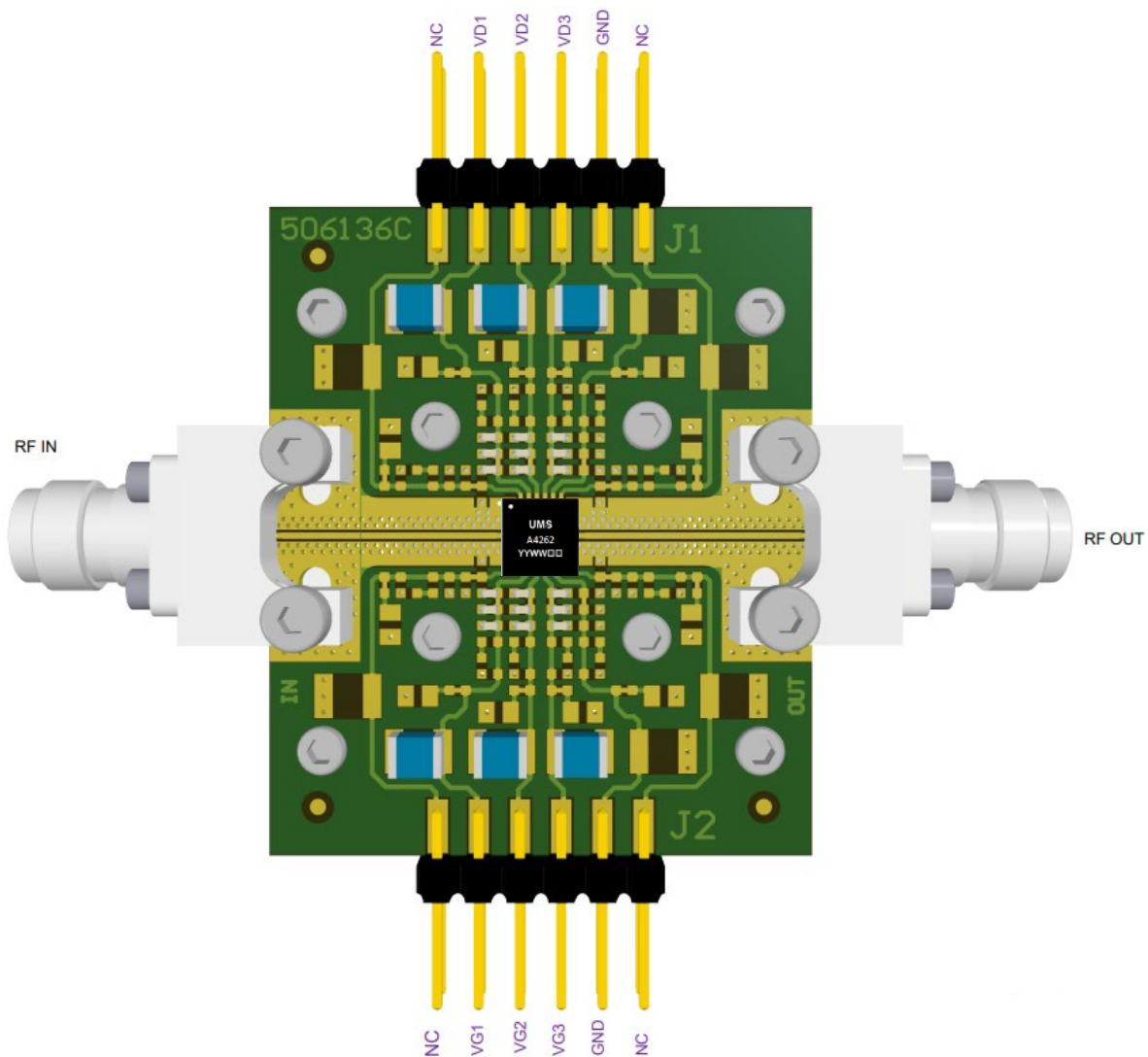
**Recommended circuit bonding table**

Label	Pin	Type	Decoupling	Comment
RF IN, RF OUT	4, 15	RF access	NA	-
VD1, VD2, VD3	23, 22, 21	Vd	120pF, 10nF & 1µF	Drain Supply
VG1, VG2, VG3	8, 9, 10	Vg	120pF, 10nF & 1µF	Gate Supply

## Evaluation board

- Compatible with the proposed footprint.
- Based on typically Ro4350B / 8mils or equivalent.
- Using a micro-strip to coplanar transition to access the package.
- Recommended for the implementation of this product on a module board.
- Decoupling capacitors of 120pF, 10nF & 1 $\mu$ F  $\pm$ 10% are recommended for all DC access.
- See application note AN0017 for more details.

Note: All board measurements are performed using **shielded cables, even for DC bias, to ensure safe operation.**



## **Recommended package footprint**

Refer to the application note AN0017 available at <http://www.ums-rf.com> for package foot print recommendations.

## **SMD mounting procedure**

For the mounting process standard technics involving solder paste and a suitable reflow process can be used. For further details, see application note AN0017 available at <http://www.ums-rf.com>.

## **Recommended environmental management**

UMS products are compliant with the regulation in particular with the directives RoHS N°2011/65 and REACH N°1907/2006. More environmental data are available in the application note AN0019 also available at <http://www.ums-rf.com>.

## **Recommended ESD management**

Refer to the application note AN0020 available at <http://www.ums-rf.com> for ESD sensitivity and handling recommendations for the UMS package products.

## **Description of Evaluation Board**

Refer to the application note AN0031 available at <https://www.ums-rf.com> for the description of Evaluation Board for Packaged Die and recommendations for this UMS package product.

Ordering request reference

Package: CHA4262-QDG/XY  
Stick: XY = 20

Tape & reel: XY = 21

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